

Notice of References Cited

Application/Control No.

09/607,580

Applicant(s)/Patent Under
Reexamination
WU ET AL.

Examiner

Charles A Harkness

Art Unit

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Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,742,805	04-1998	Kulkarni et al.	712/239
	B	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Huang, Jian et al. "Exploiting Basic Block Value Locality with Block Reuse", Jan 13, 2003, Fifth International Symposium On High-Performance Computer Architecture, 1999. Proceedings. pages 106-114.
	V	Gonzalez, Antonio et al. "Trace-Level Reuse", 09/24/99, 1999 International Conference on Parallel Processing, 1999. Proceedings. pages 30-37.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.